

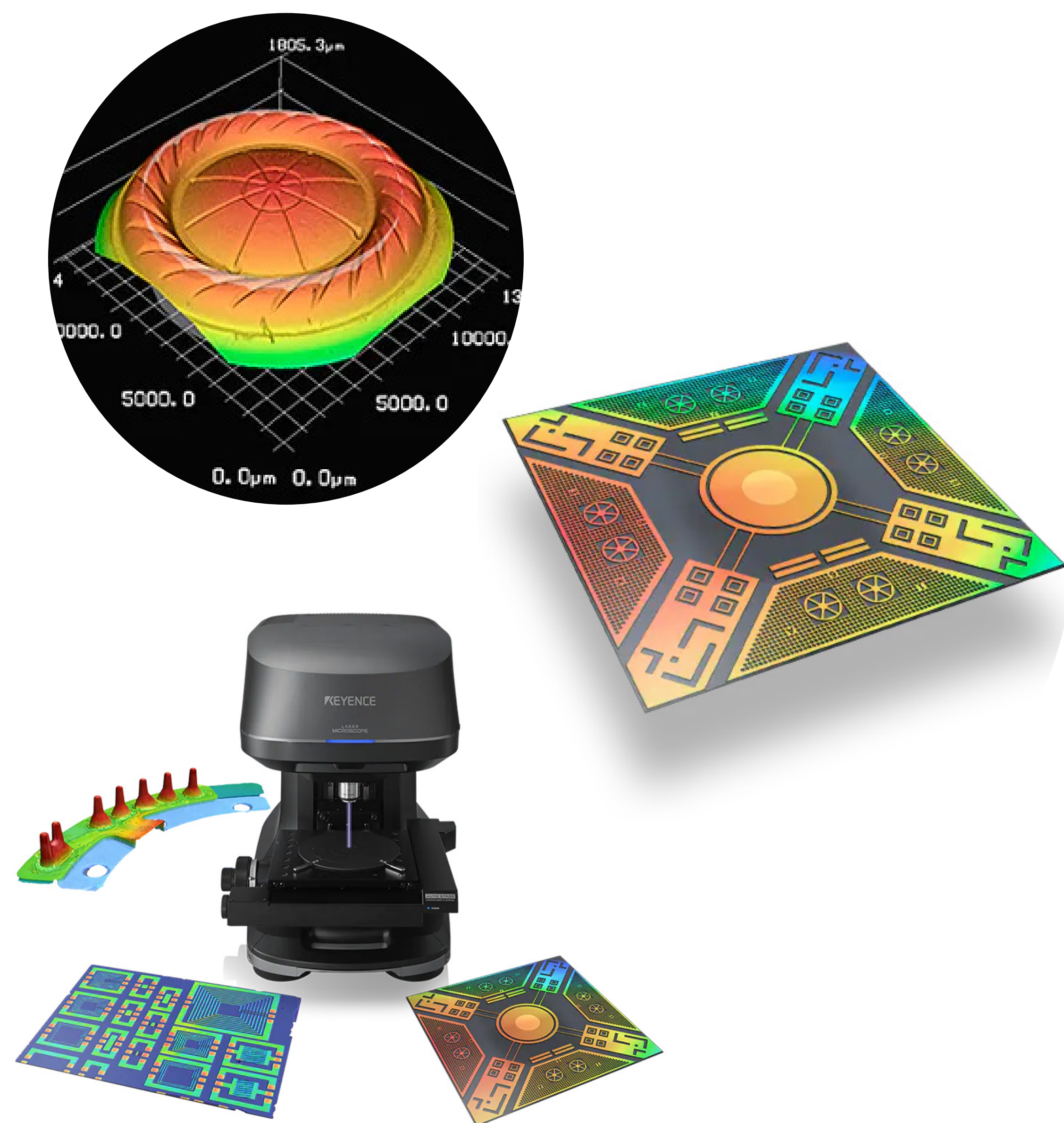


Georgia Tech
Institute for Materials

MEASUREMENT & CHARACTERIZATION

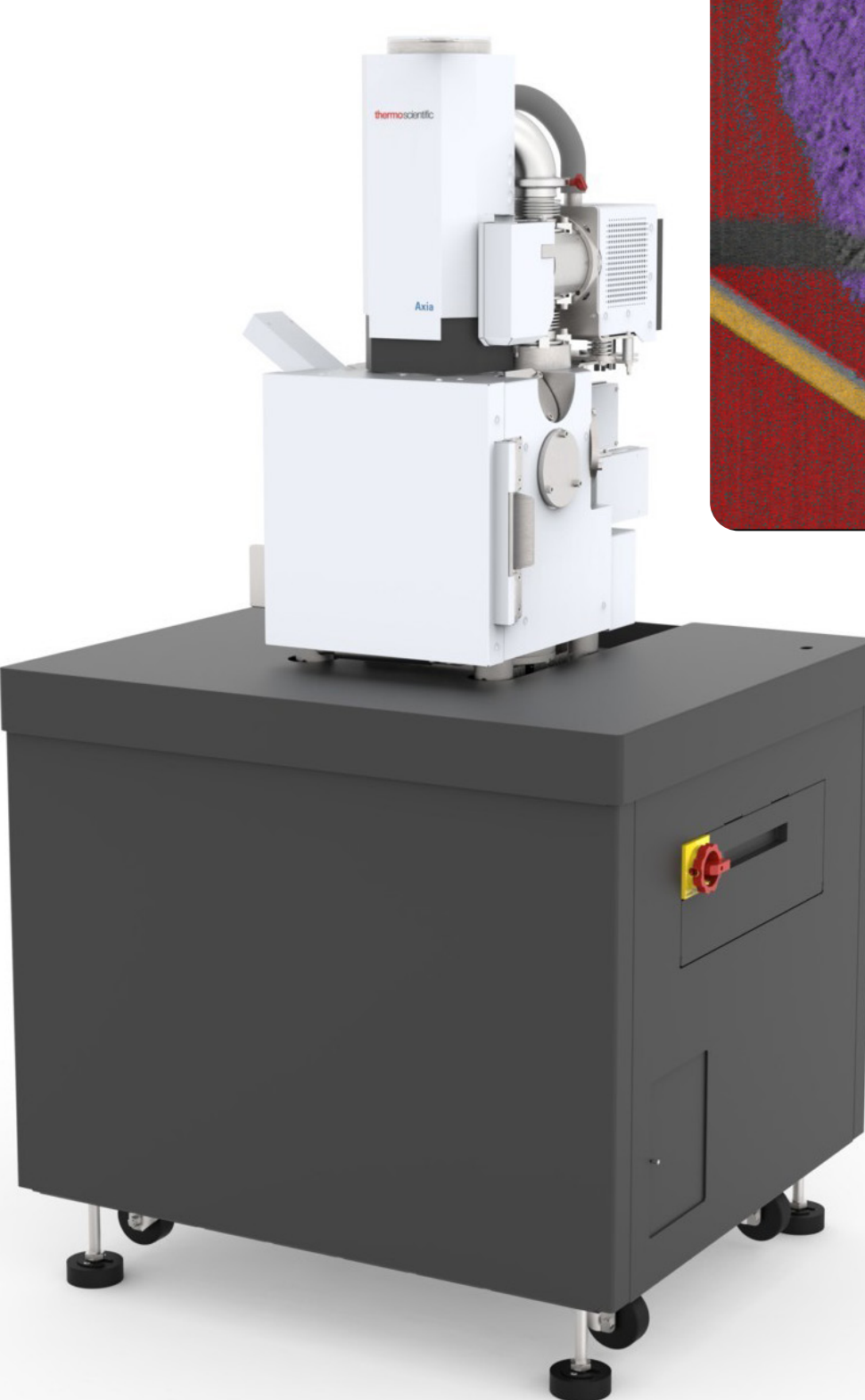
DEMO DAY IN PETTIT 160

December 2nd & 3rd | 10:00AM – 5:00 PM



Keyence VKX-3100

3D optical imaging and profiling.
Vertical / Lateral resolution down to 0.1 nm / 500 nm
Automatic measurement and analysis SW



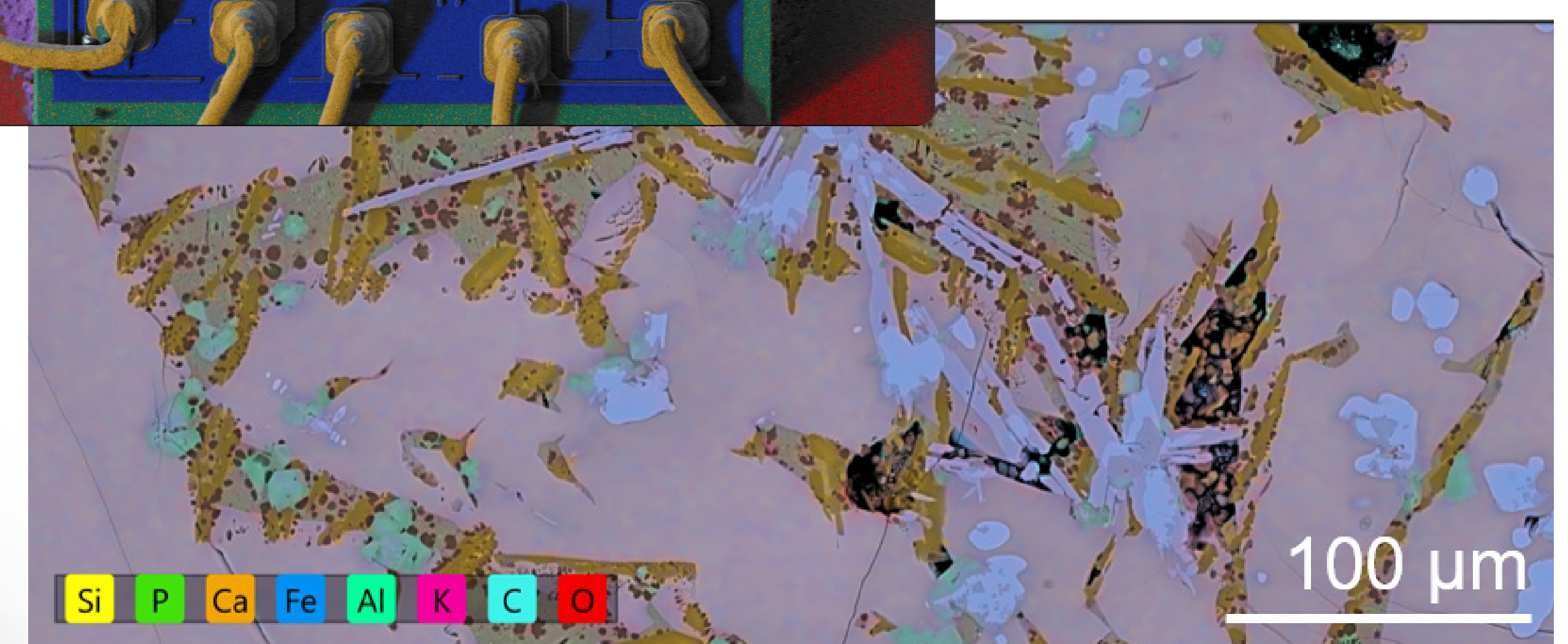
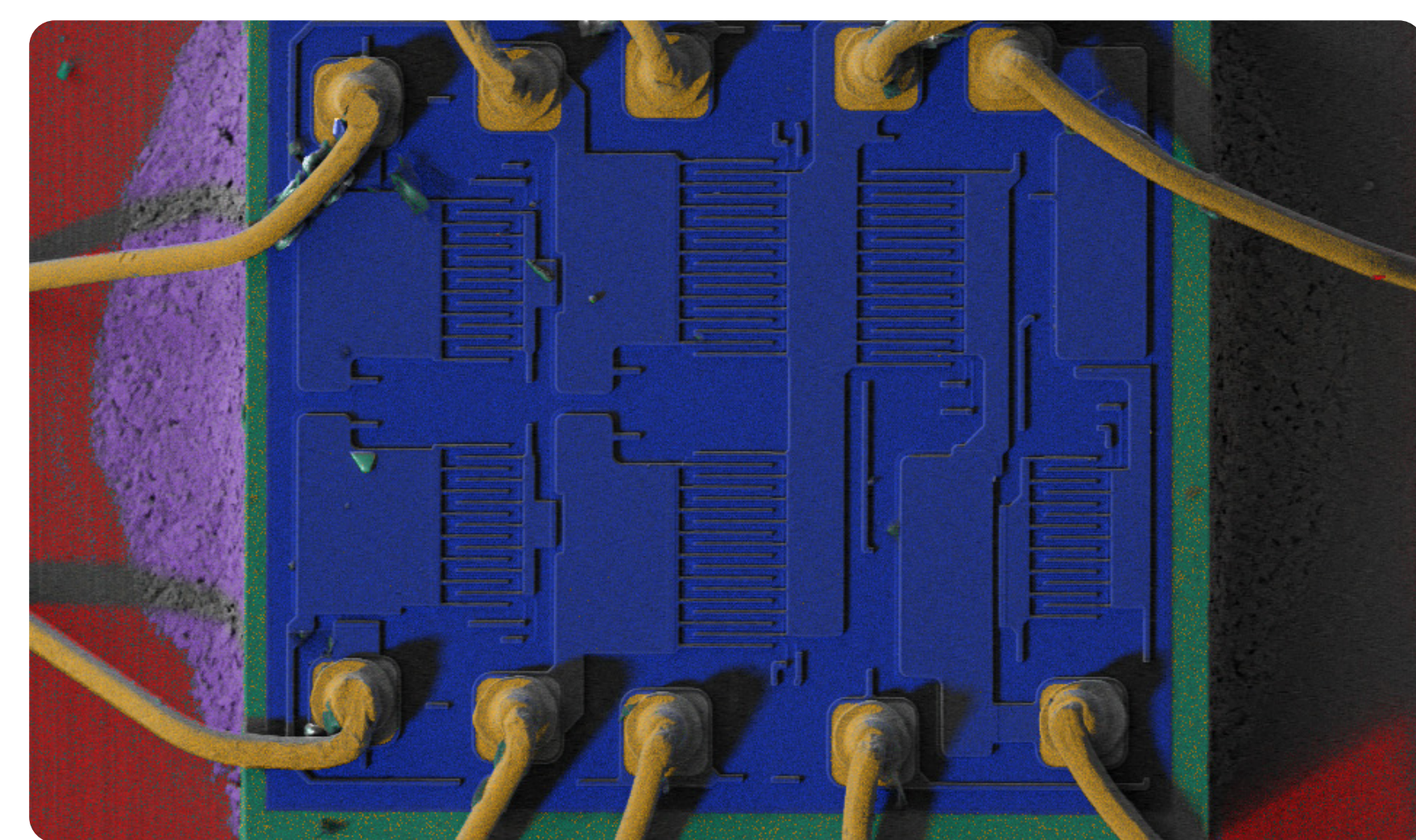
Axia ChemiSEM

Variable-pressure SEM
Real-time elemental mapping
Automatic measurement and analysis SW
Largest weight capacity of any SEM



Dage X-Ray XD7600NT

X-ray imaging with resolution down to 600 nm
Oblique imaging up to a 70 °angle
Automatic BGA and void measurements



MEET THE STAFF
COME SEE & USE THE TOOLS
DISCUSS YOUR MEASUREMENT NEEDS

FREE DEMONSTRATIONS AND MEASUREMENTS
BRING YOUR SAMPLES!